

N-Channel 30 V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	R _{DS(on)} (Ω) MAX.	I _D (A) ^a	Q _g (TYP.)			
30	0.0045 at V _{GS} = 10V	60	9.7 nC			
30	0.0060 at V _{GS} = 4.5 V	46	9.7 110			

FEATURES

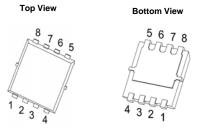
- TrenchFET® power MOSFET
- 100 % R_g and UIS tested

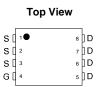
APPLICATIONS

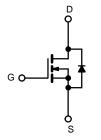
- High power density DC/DC
- Synchronous rectification
- Embedded DC/DC



DFN 3.3x3.3







N-Channel MOSFET

PARAMETER	SYMBOL	LIMIT	UNIT	
Drain-Source Voltage	V _{DS}	30	V	
Gate-Source Voltage		V _{GS}	+20	v
	T _C = 25 °C		60	
Continuous Drain Current /T 150 °C\	T _C = 70 °C	l , 🗀	47	
Continuous Drain Current (T _J = 150 °C)	T _A = 25 °C	I _D	20.6 b, c	
	T _A = 70 °C		17.1 ^{b, c}	
Pulsed Drain Current (t = 300 μs)		I _{DM} 180	180	Α
Continuous Source-Drain Diode Current	T _C = 25 °C		15.3	
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	4.8 b, c	
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	17	
Single Pulse Avalanche Energy	L = U. I IIIII	E _{AS}	15.37	mJ
	T _C = 25 °C		35.1	
Maximum Dayyar Dissination	T _C = 70 °C		20	10/
Maximum Power Dissipation	T _A = 25 °C	P _D	3.9 b, c	W
	T _A = 70 °C		2.7 b, c	
Operating Junction and Storage Temperature R	T _J , T _{stg}	-55 to 150	°C	
Soldering Recommendations (Peak Temperatur		260	-0	

THERMAL RESISTANCE RATINGS						
PARAMETER		SYMBOL	TYPICAL	MAXIMUM	UNIT	
Maximum Junction-to-Ambient b, f	t ≤ 10 s	R _{thJA}	24	31	°C/W	
Maximum Junction-to-Case (Drain)	Steady State	R _{thJC}	3	4	C/VV	

Notes

- a. Based on T_C = 25 °C. b. Surface mounted on 1" x 1" FR4 board.
- d. The DFN3.3X3.3 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- e. Rework conditions: Manual soldering with a soldering iron is not recommended for leadless components.
- f. Maximum under steady state conditions is 70 °C/W.

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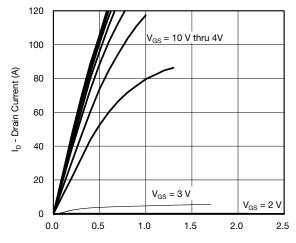
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static	l .			•	l	<u> </u>
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	30	-	- ,	
Drain-Source Breakdown Voltage (transient) ^c	V _{DSt}	$V_{GS} = 0 \text{ V}, I_{D(aval)} = 15 \text{ A}, t_{transient} = 50 \text{ ns}$	36	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$		-	20	-	mV/°
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA	-	-4.6	-	С
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	1.0	-	3.0	V
Gate-Source Leakage	I _{GSS}	V _{DS} = 0 V, V _{GS} = 20V	-	-	± 100	nA
7. 0.1 1/1 1/2 1/2 1/2		$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$	-	-	1	μA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 30 V, V _{GS} = 0 V, T _J = 55 °C	-	-	10	
On-State Drain Current ^a	I _{D(on)}	V _{DS} ≥ 5 V, V _{GS} = 10 V	60	-	-	Α
	` ′	V _{GS} = 10 V, I _D = 10 A	-	0.0045	0.0053	Ω
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 4.5 V, I _D = 8 A	-	0.0060	0.0066	
Forward Transconductance ^a	g _{fs}	V _{DS} = 10 V, I _D = 10 A	-	67	-	S
Dynamic ^b				l.	L	
Input Capacitance	C _{iss}		-	1630	-	
Output Capacitance	Coss	V _{DS} = 15 V, V _{GS} = 0 V, f = 1 MHz		445	-	pF
Reverse Transfer Capacitance	C _{rss}			38	-	
C _{rss} /C _{iss} Ratio			-	26	52	-
	_	V _{DS} = 15 V, V _{GS} = 10 V, I _D = 10 A	-	19.4	29	nC
Total Gate Charge	Q_g		-	9.7	14	
Gate-Source Charge	Q _{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 10 \text{ A}$	-	4	-	
Gate-Drain Charge	Q _{qd}		-	1.8	-	
Output Charge	Q _{oss}	V _{DS} = 15 V, V _{GS} = 0 V	-	12.5	-	
Gate Resistance	R _q	f = 1 MHz	0.4	1.65	3.3	Ω
Turn-On Delay Time	t _{d(on)}		-	9	18	
Rise Time	t _r	$V_{DD} = 15 \text{ V, R}_{L} = 1.5 \Omega$	-	8	16	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 10 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$	-	18	36	
Fall Time	t _f		-	8	16	
Turn-On Delay Time	t _{d(on)}		-	15	30	ns
Rise Time	t _r	$V_{DD} = 15 \text{ V, R}_{I} = 1.5 \Omega$	-	12	24	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 10 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$	-	18	36	
Fall Time	t _f	_	-	9	18	
Drain-Source Body Diode Characteristics	<u>'</u>				<u> </u>	
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C	-	_	15.3	
Pulse Diode Forward Current ^a	I _{SM}	-	-	-	180	A
Body Diode Voltage	V _{SD}	I _S = 3 A	-	0.76	1.1	V
Body Diode Reverse Recovery Time	t _{rr}	j j	-	24	48	ns
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = 10 A, dl/dt = 100 A/μs,	-	14	28	nC
Reverse Recovery Fall Time	ta	$T_{\text{J}} = 25 ^{\circ}\text{C}$	-	12	-	
Reverse Recovery Rise Time	t _b	-		12	-	ns

Notes

- a. Pulse test; pulse width \leq 300 μ s, duty cycle \leq 2 %.
- b. Guaranteed by design, not subject to production testing.
- c. $T_{CASE} = 25$ °C. Expected voltage stress during 100 % UIS test. Production datalog is not available.

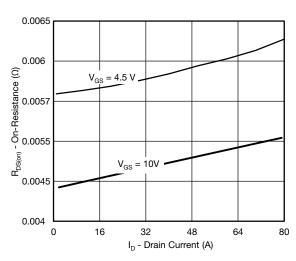
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



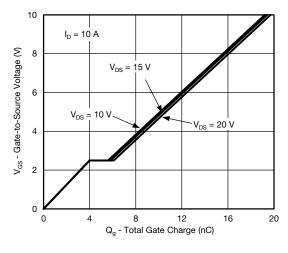


 ${\rm V}_{\rm DS}$ - Drain-to-Source Voltage (V)

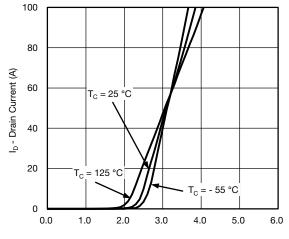
Output Characteristics



On-Resistance vs. Drain Current

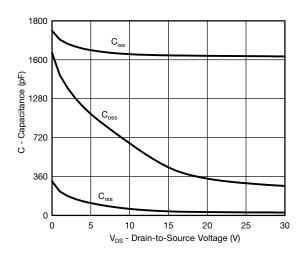


Gate Charge

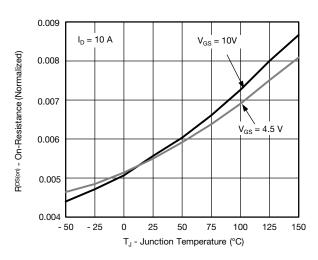


 V_{GS} - Gate-to-Source Voltage (V)

Transfer Characteristics

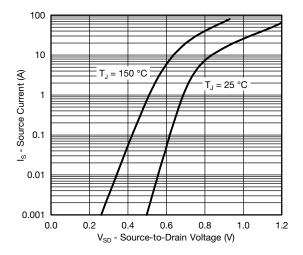


Capacitance

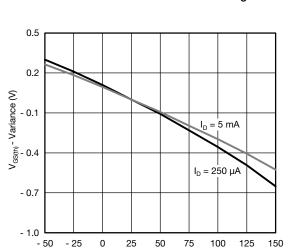


On-Resistance vs. Junction Temperature



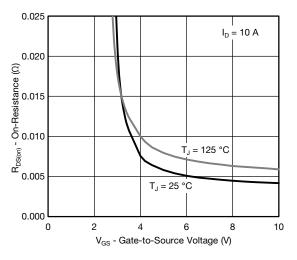


Source-Drain Diode Forward Voltage

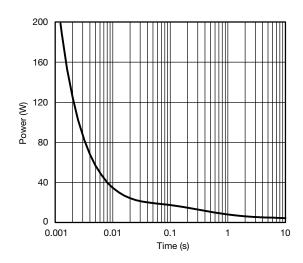


Threshold Voltage

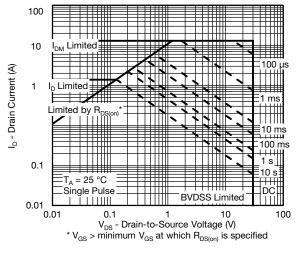
T_J - Temperature (°C)



On-Resistance vs. Gate-to-Source Voltage

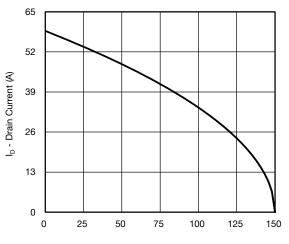


Single Pulse Power, Junction-to-Ambient



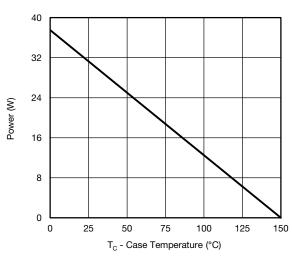
Safe Operating Area



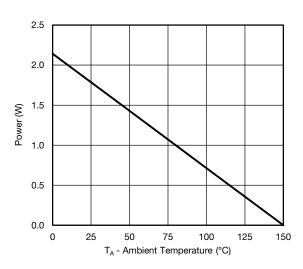


T_C - Case Temperature (°C)

Current Derating*



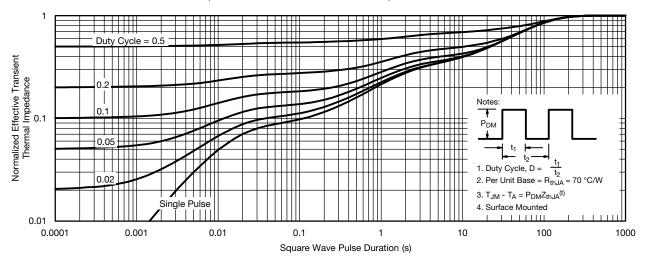




Power, Junction-to-Ambient

 $^{^*}$ The power dissipation P_D is based on $T_{J \text{ (max.)}} = 150 \,^{\circ}\text{C}$, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





Normalized Thermal Transient Impedance, Junction-to-Ambient

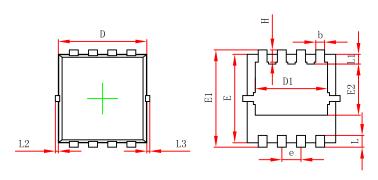


Normalized Thermal Transient Impedance, Junction-to-Case



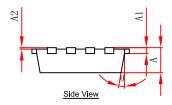
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DFN3.3x3.3-8L Package Outline Dimensions



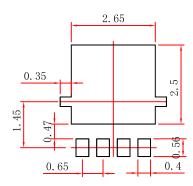


Bottom View



Symbol	Dimensions	In Millimeters	Dimensions In Inches		
	Min.	Max.	Min.	Max.	
Α	0.650	0.850	0.026	0.033	
A1	0.152	REF.	0.006 REF.		
A2	0~0	0.05	0~0.002		
D	2.900	3.100	0.114	0.122	
D1	2.300	2.600	0.091	0.102	
E	2.900	3.100	0.114	0.122	
E1	3.150	3.450	0.124	0.136	
E2	1.535	1.935	0.060	0.076	
b	0.200	0.400	0.008	0.016	
е	0.550	0.750	0.022	0.030	
L	0.300	0.500	0.012	0.020	
L1	0.180	0.480	0.007	0.019	
L2	0~0.100		0~0.004		
L3	0~0.100		0~0.004		
Н	0.315	0.515	0.012	0.020	
θ	9°	13°	9°	13°	

DFN3.3x3.3-8L Suggested Pad Layout







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